

Atomic-Resolution Characterization of Interfaces in Poly-Crystalline CdTe Devices

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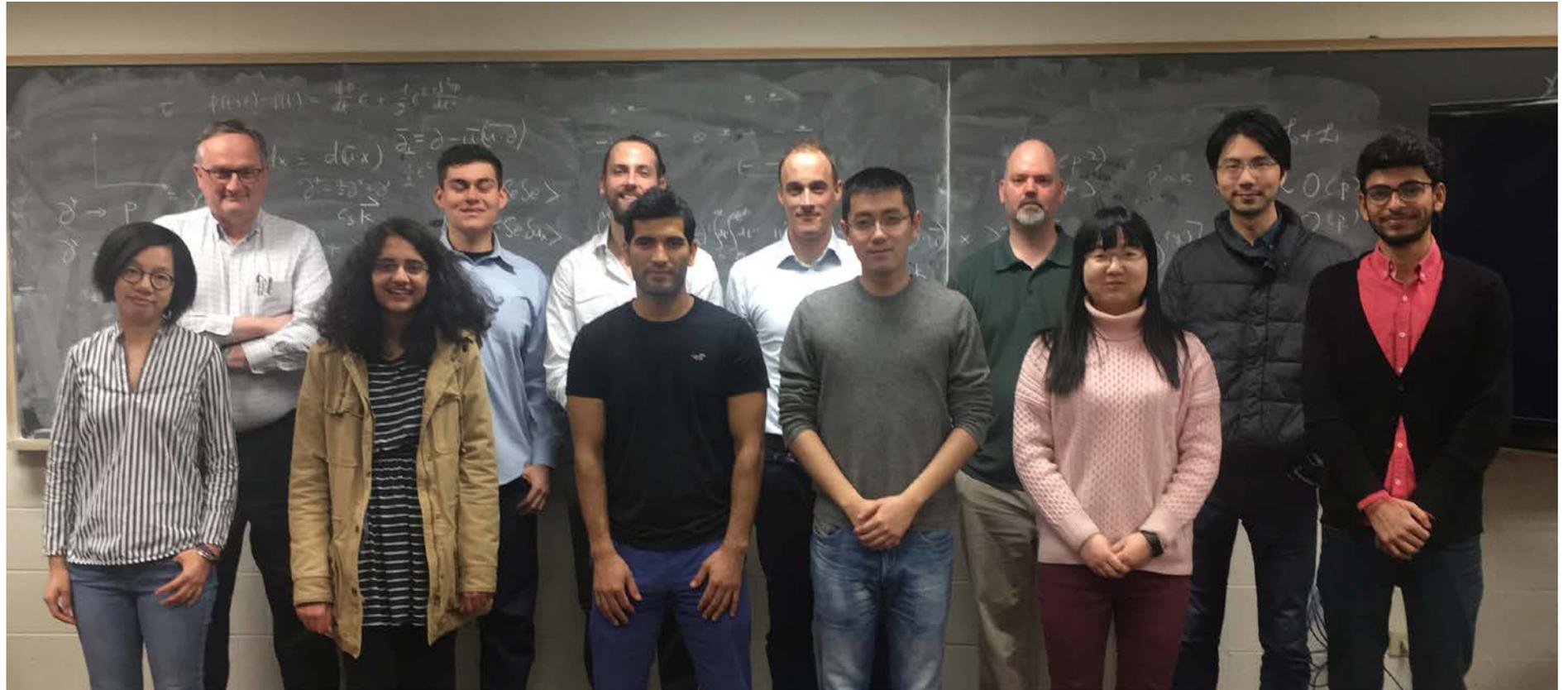
S. Walajabad and J. Sites

Colorado State University

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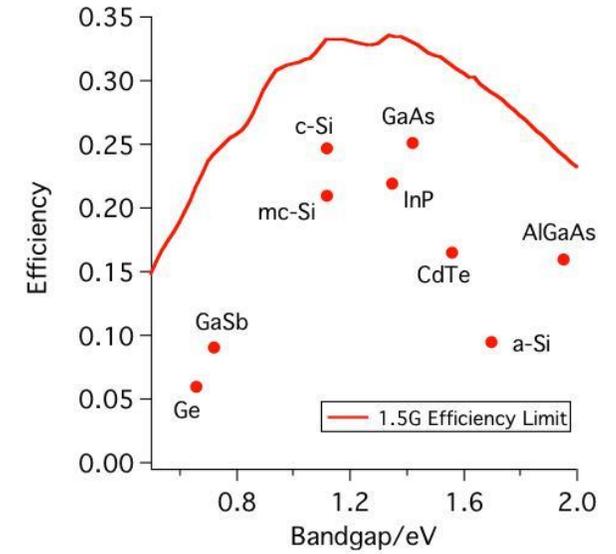
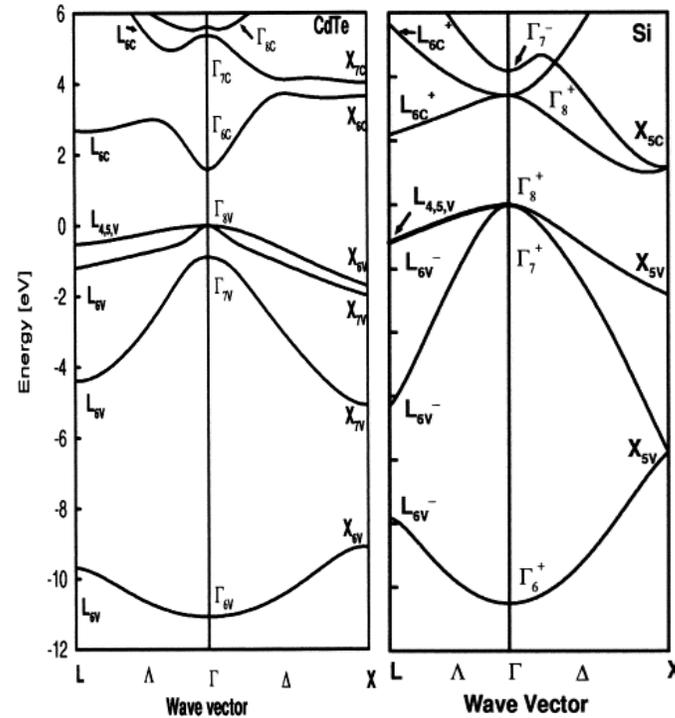
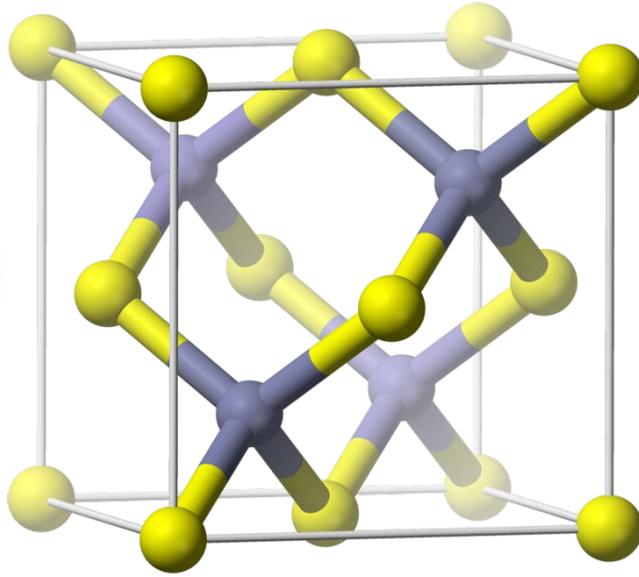


DOE SunShot EE0007545, EE0008557, EE0008974

Virtual Chalcogenide PV Conference 2020
May 26th, 2020

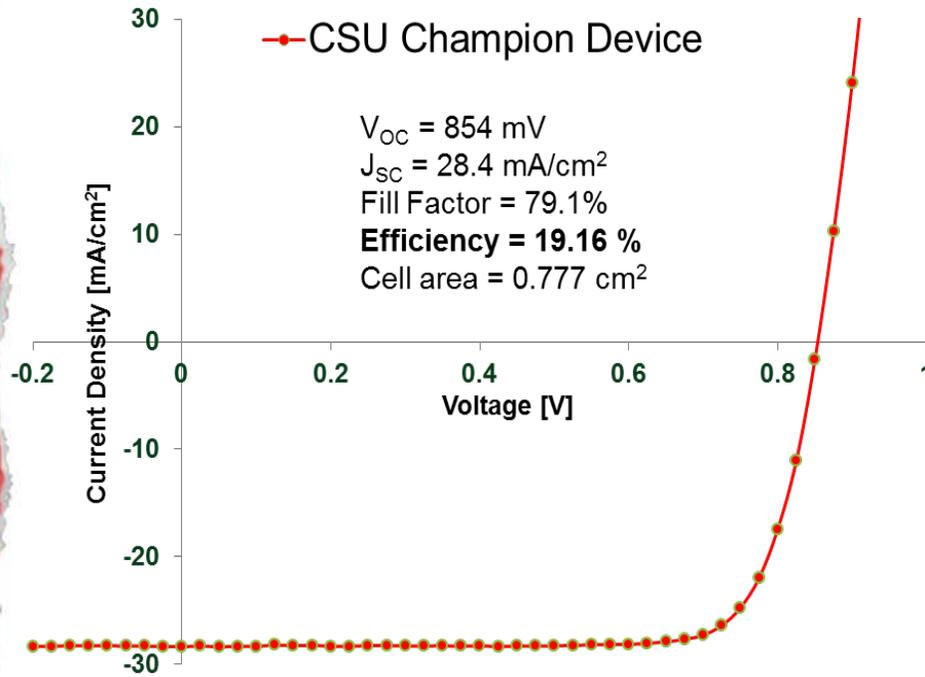


Cadmium Telluride

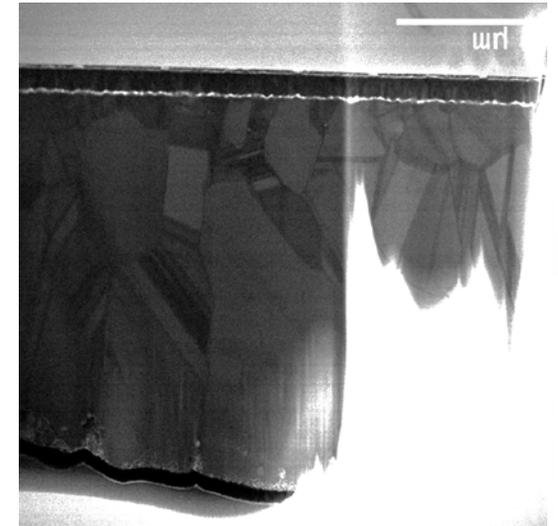
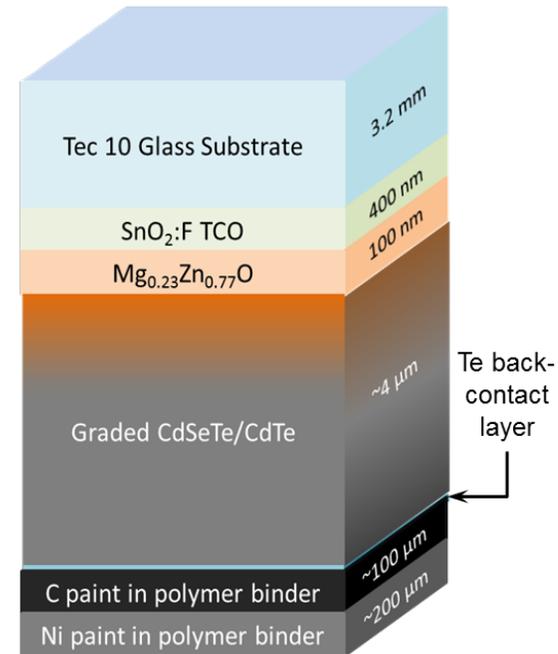


- Nearly **ideal** direct optical band gap (~ 1.45 eV)
- High **absorption coefficient** (99% absorption in $2 \mu\text{m}$) enabling thin film technology
- Fast/cheap processing can still yield **high efficiency**
 - Cost-effective PV devices
 - Economically viable for **production**

CdTe Solar Cells

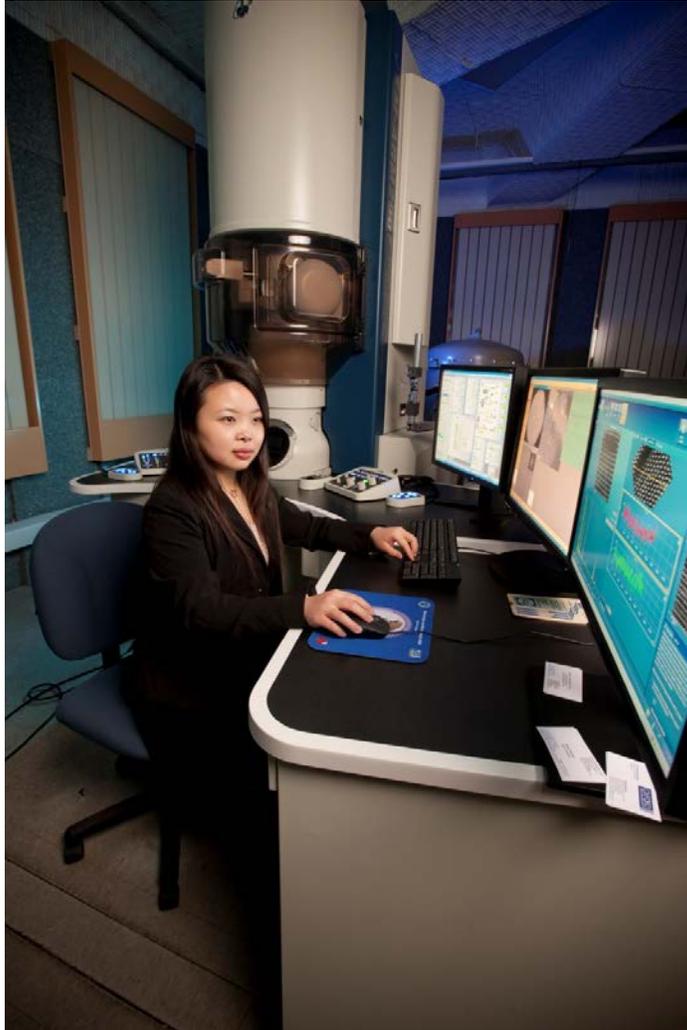


No anti-reflection coating



Grain boundaries and interface recombination appear to be the most significant limits!

JEOL JEM-ARM 200CF at UIC



- Cold field emission (0.35 eV resolution)
- Probe spherical aberration corrector (less than 70pm spatial resolution)
- Oxford XMax100TLE
- HAADF detectors, BF detector and ABF detector
- Heating, Cooling, Liquid, STM, Vacuum Transfer and Tomography stages.
- Gatan Continuum GIF

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Virtual Chalcogenide PV Conference 2
May 26th, 2020

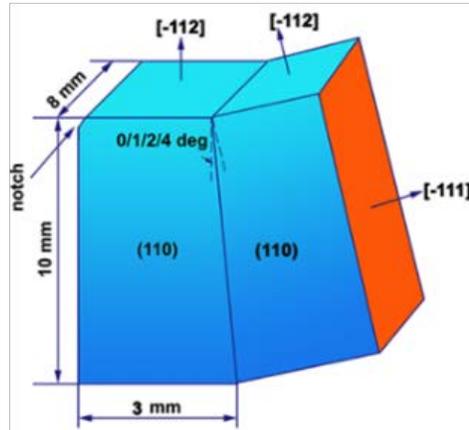


NSF – DMR-1408427
NSF – DMR -0959470

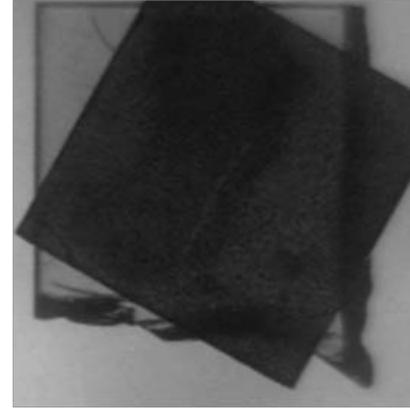


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Group

CdTe Bi-Crystals



Schematic of bi-crystal



IR image of bi-crystal



Jinglong Guo

in collaboration with M. Chan (ANL) Moon Kim (UT Dallas),

A. Rocket (CSM) and M. Nardone (BGSU)

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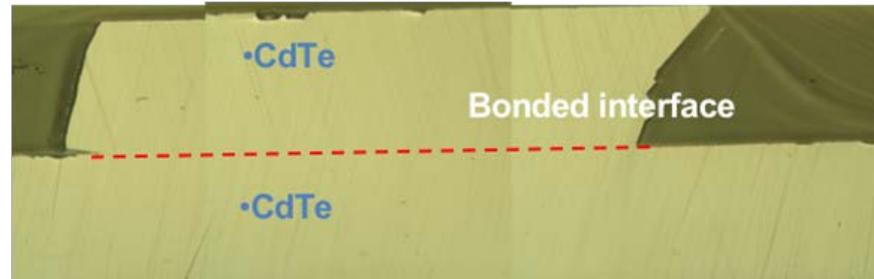
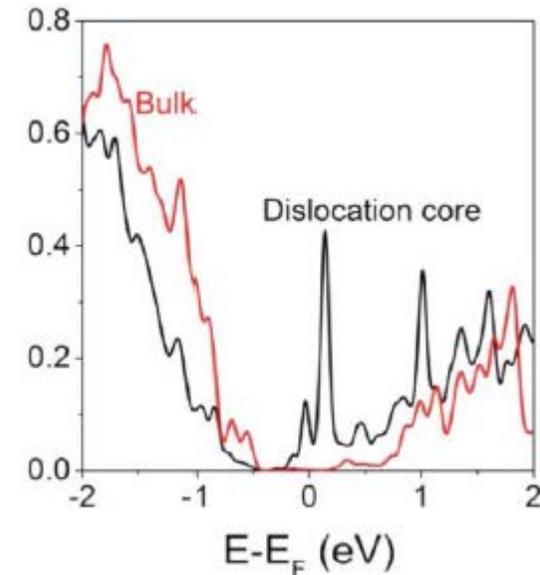
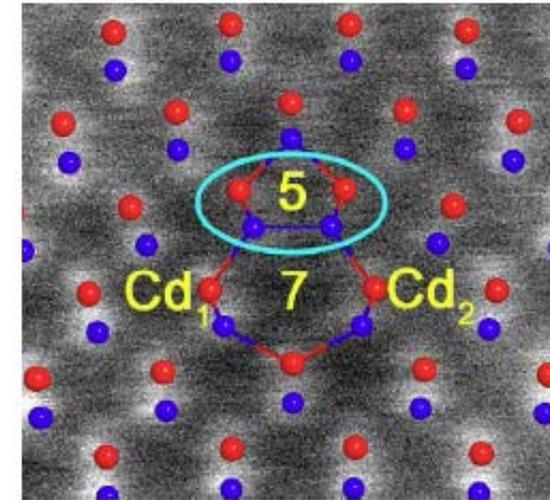
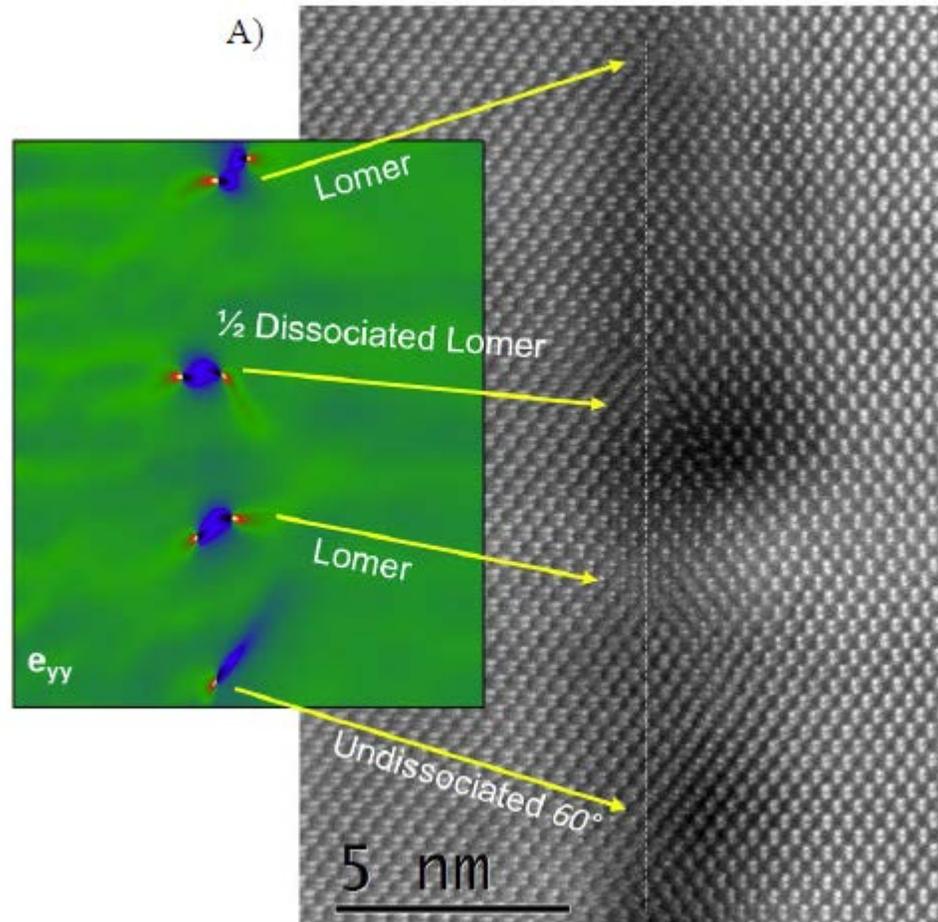


Image of bi-crystal

- CdTe (111) wafers
 - $[112]_1 // [011]_2$
 - $[0-11]_1 // [01-1]_2$
 - $[0-11]_1 // [0-11]_2$
 - Small angle (5°) Tilt
 - Small angle (2°) Tilt
- CdTe (110) wafers
 - $[1-1-2]_1 // [-111]_2$
 - Small angle (4°) Tilt
- CdTe (100) wafers
 - $[011]_1 // [011]_2$
- CdTe (211) wafers
 - $[0-11]_1 // [01-1]_2$
- CdZnTe (111) wafers
 - $[0-11]_1 // [011]_2$
- CdTe (100)/CdTe(110)
 - $[0-11]_1 // [-111]_2$
- CdS (001)/CdTe (111)

CdTe Bi-Crystals



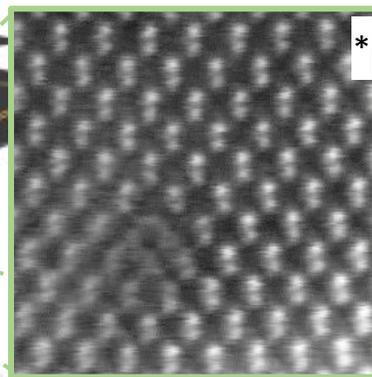
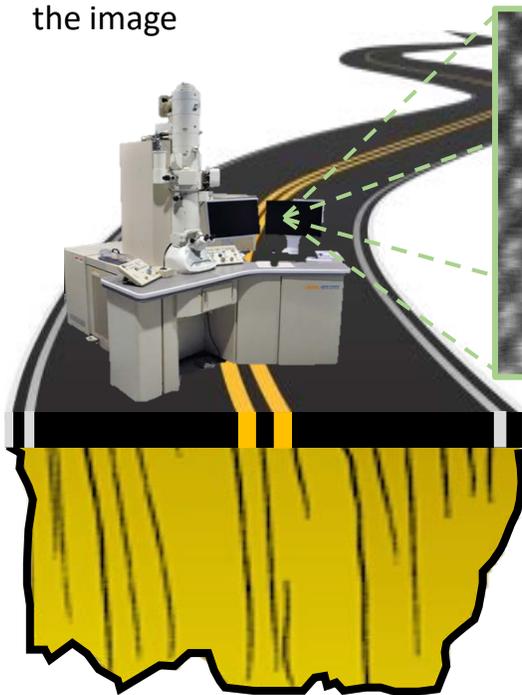
Paulauskas, PhD Thesis, University of Illinois – Chicago (2016)

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CdTe Grain Boundaries

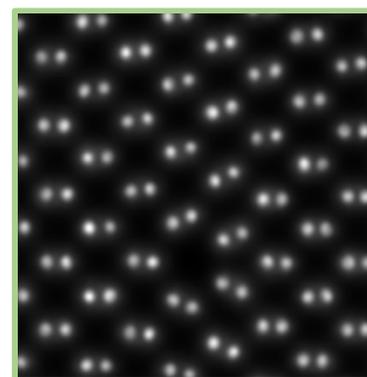
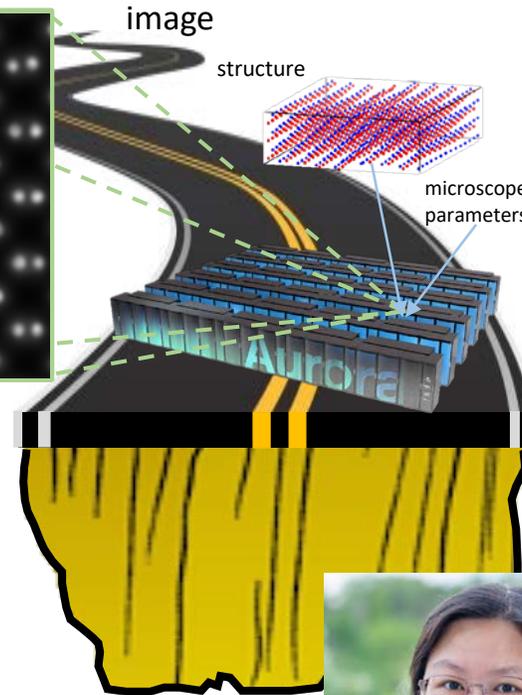
Automate the matching of experimental and computed images

Path to acquiring the image



-?-

Path to simulating the image



Are the two images similar?
If so, how similar?

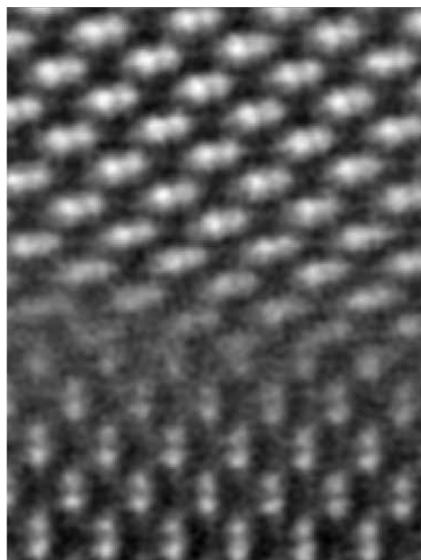
E. Schwenker et al, "Image Matching for Automated Comparisons in Atomic-Resolution Electron Microscopy," in preparation.



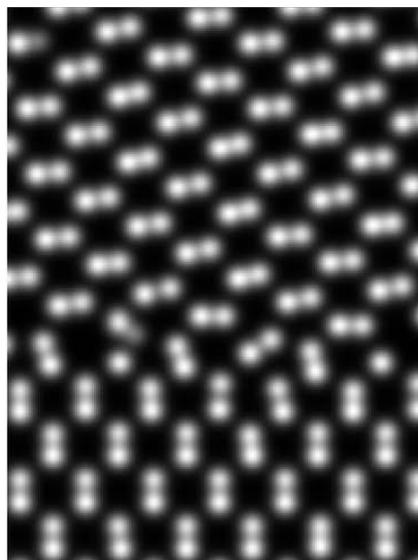
Maria Chan (ANL)

CdTe Modeling

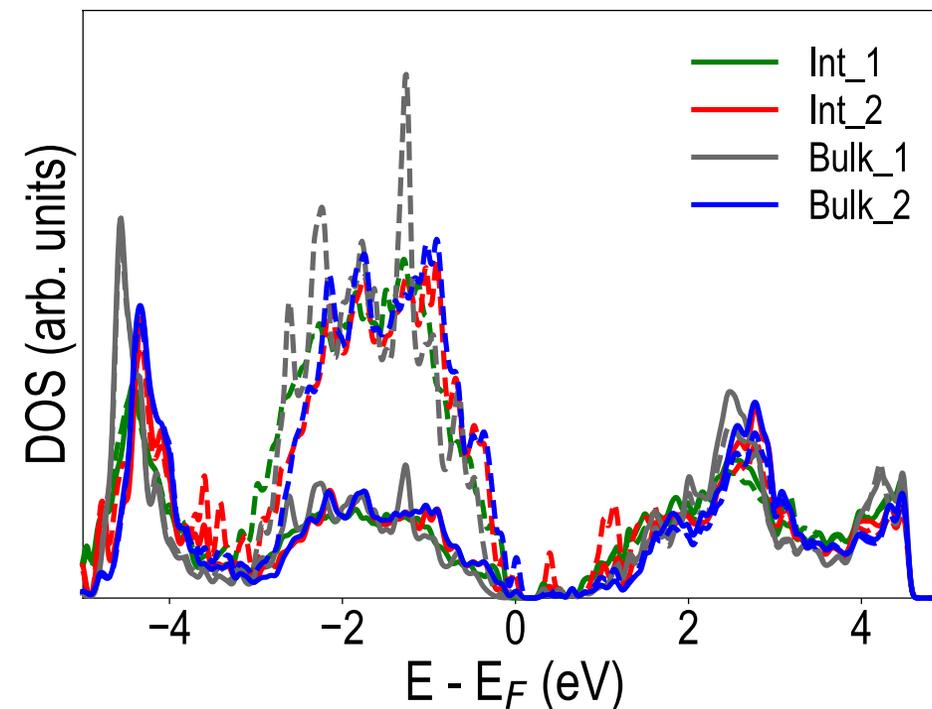
Original STEM GB image



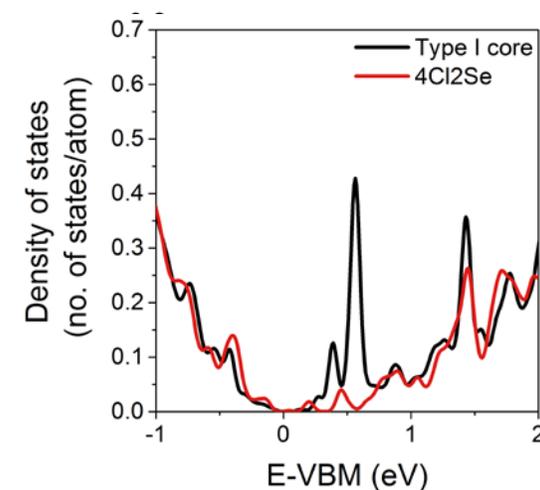
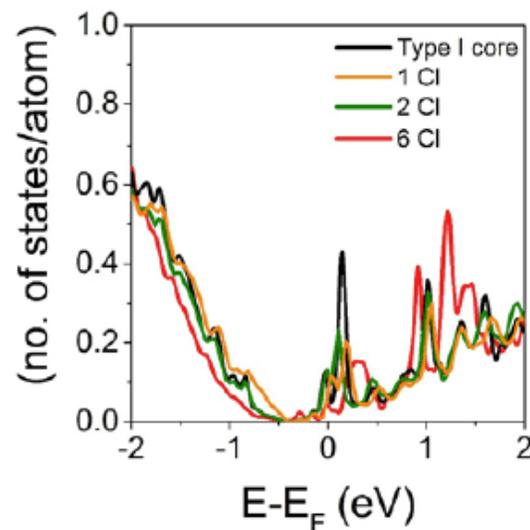
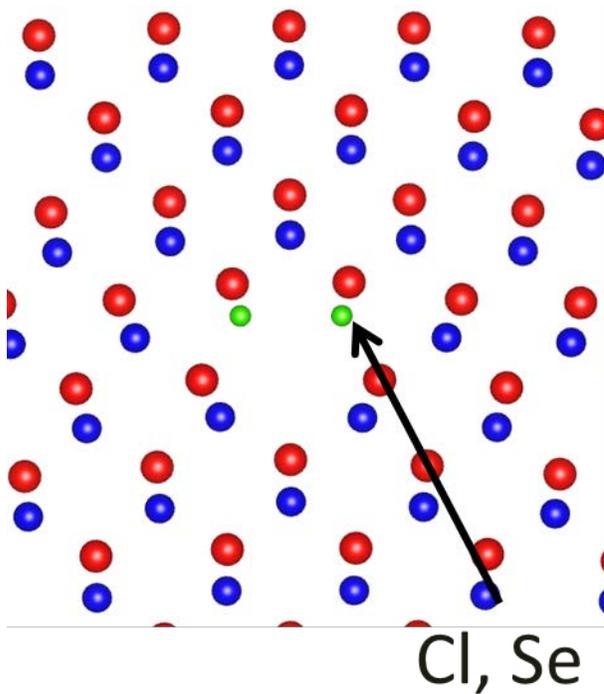
Convolution image simulation



Overlay



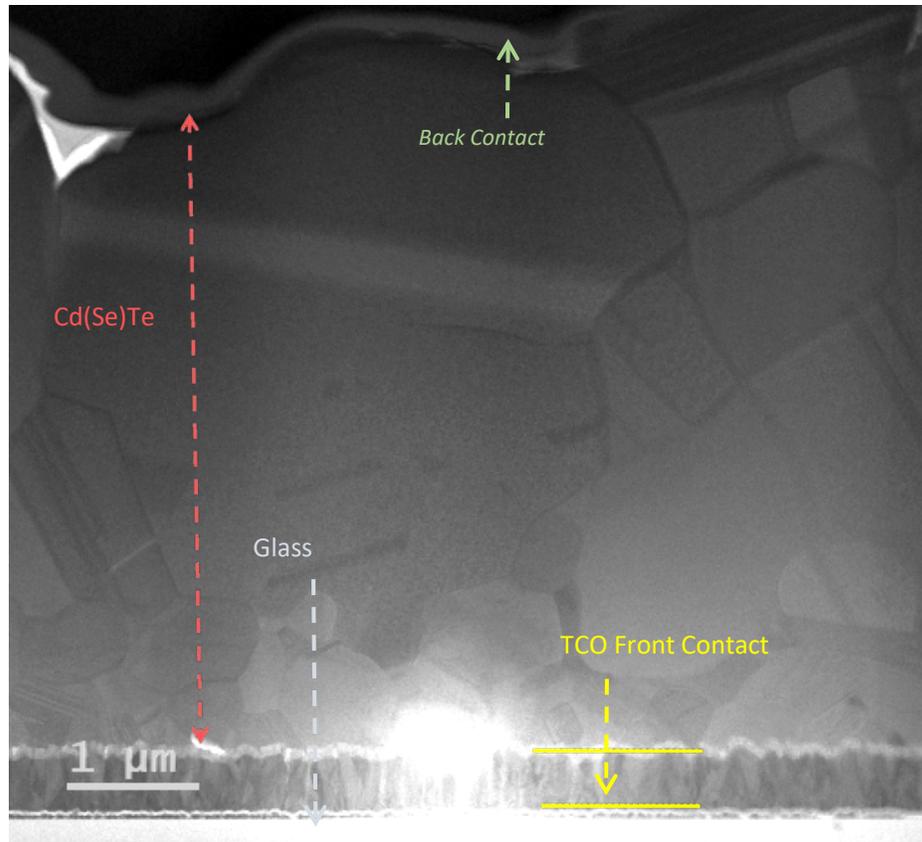
CdTe Modeling



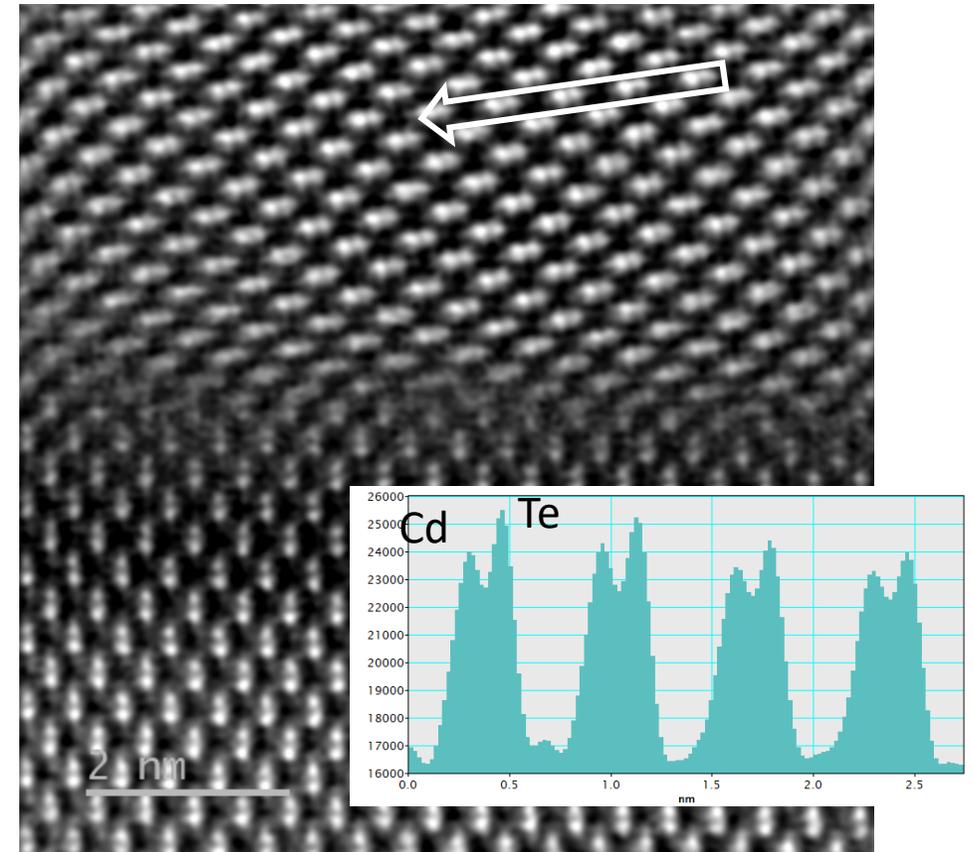
- Cl, Se can passivate defect states in the mid-gap.
- Cl and Se segregation of dopants to grain boundaries is thermodynamically favorable.
- Co-doping Se+Cl further reduces mid-gap states when substituted to dislocation core.

Imaging CdSeTe Devices

Cross-section ABF image of CdTe cell

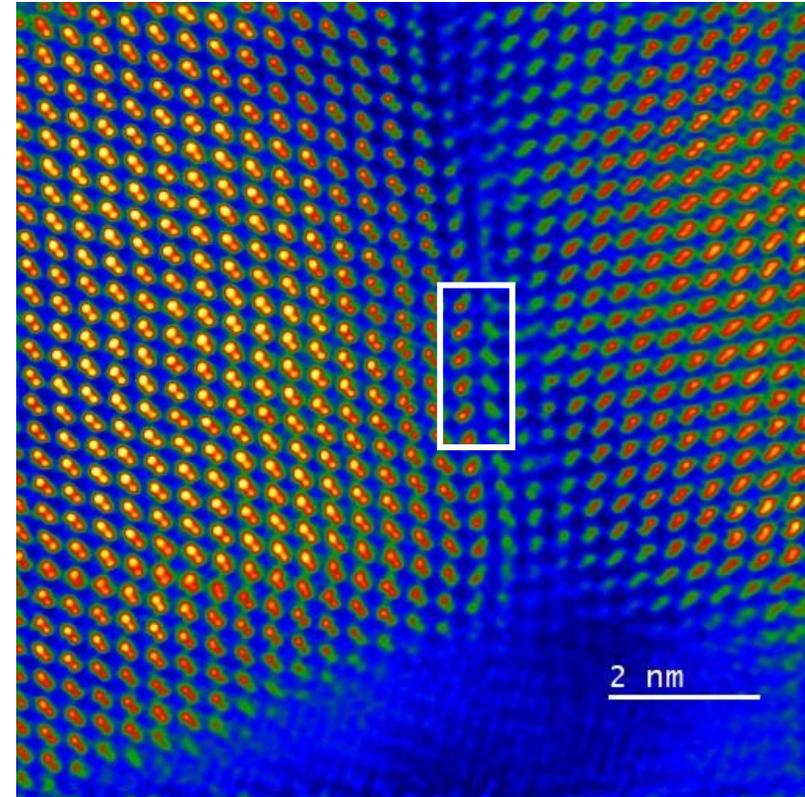
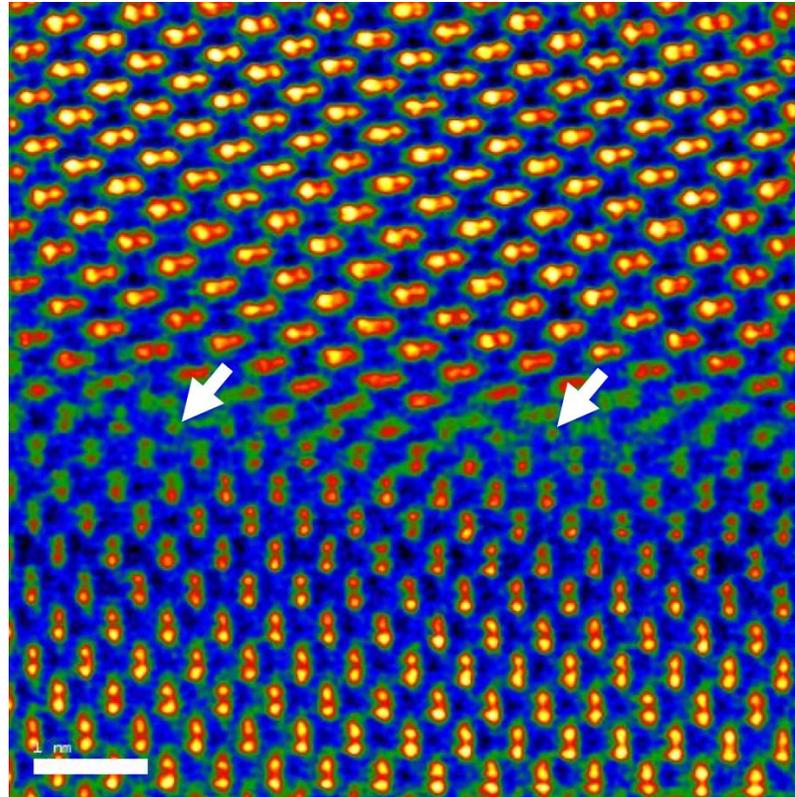


Atomic resolution HAADF image of grain boundaries in CdSeTe solar cell



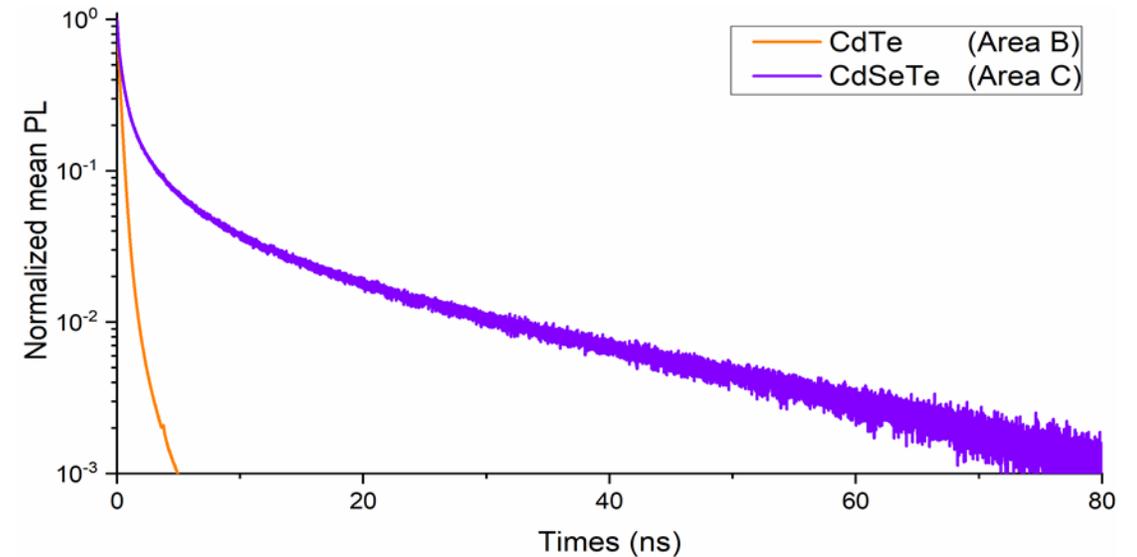
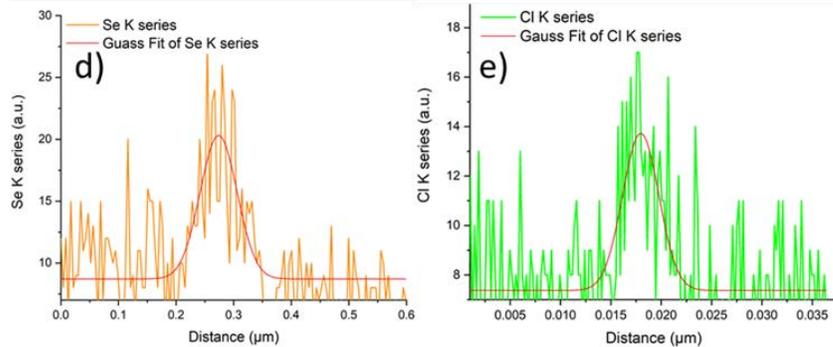
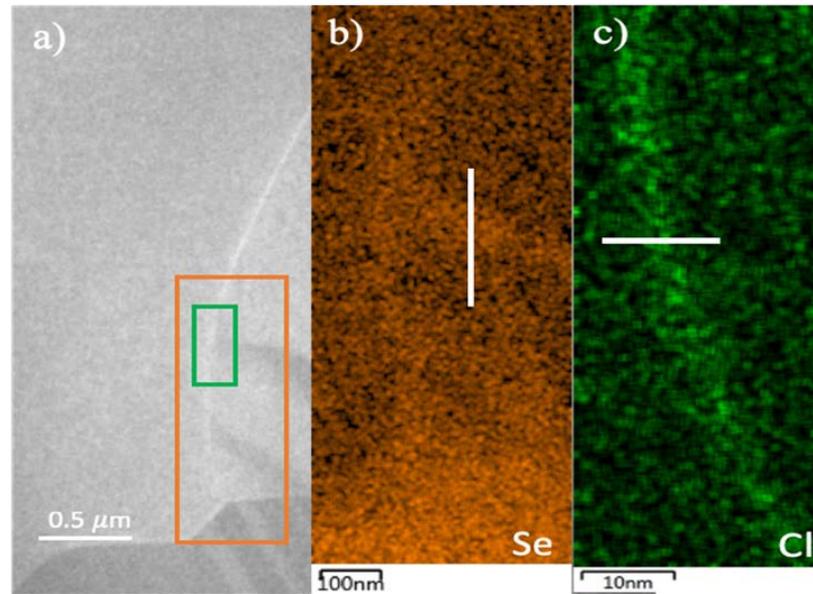
From atomic-resolution Z-contrast imaging, individual columns can be identified.

Imaging CdSeTe Devices



Atomic structure of CdSeTe grain boundaries unaffected by alloying.

Grain boundary effects

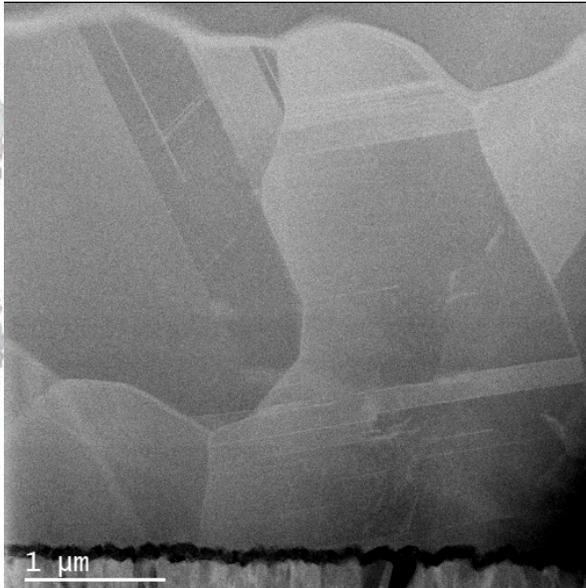


- Cl and Se co-passivate grain boundaries
- Increase in carrier lifetime

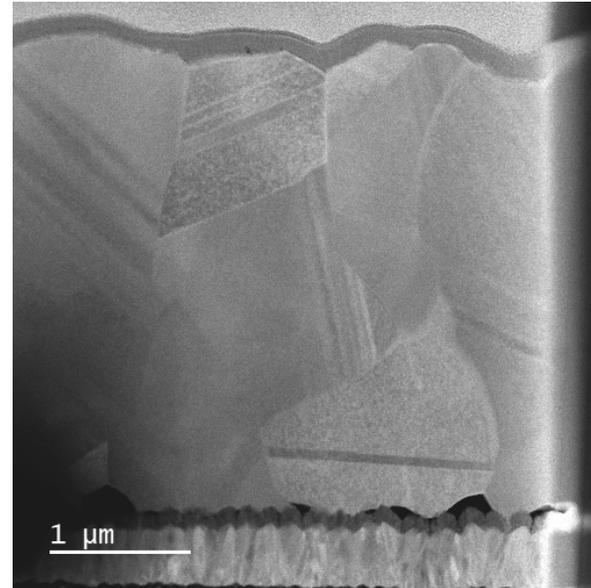
"Effect of selenium and chlorine co-passivation in polycrystalline CdSeTe devices," Guo, J.L., A. Mannodi-Kanakithodi, F.G. Sen, E. Schwenker, E.S. Barnard, A. Munshi, W. Sampath, M.K.Y. Chan, and R.F. Klie, *Applied Physics Letters*, **115**(15), (2019)

Group V doping in CdTe

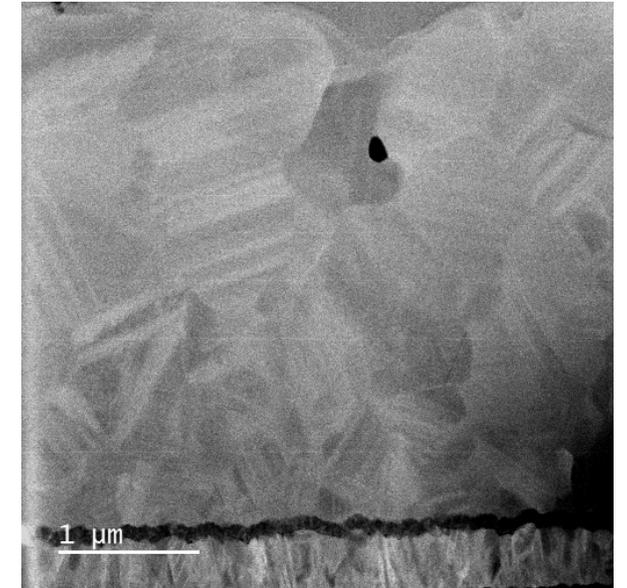
Baseline CdTe (no As)



As-doped CdTe (10^{18} cm^{-3})
Efficiency : 17%~20%

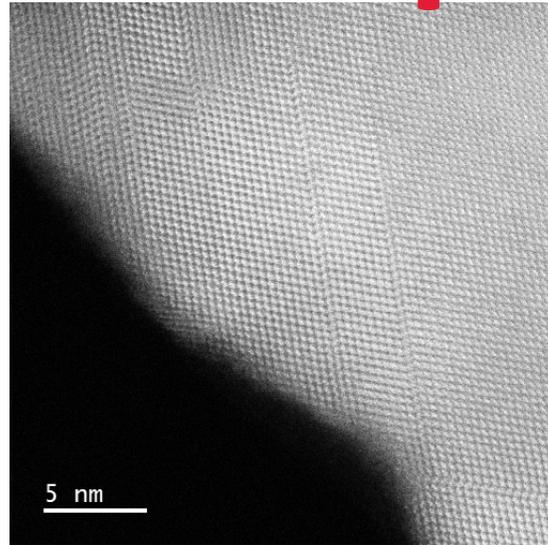


As-doped CdTe (10^{20} cm^{-3})
Efficiency : less than 2%

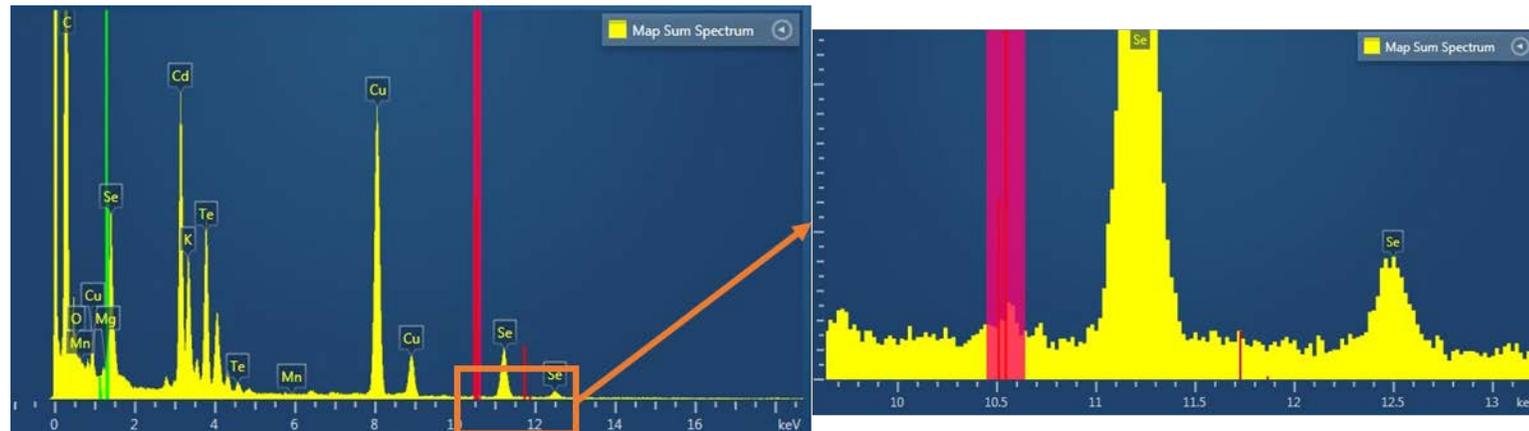


- Increasing of As doping results in smaller grain size.
- More grain boundaries and dislocations cores.
- More $\Sigma 3$ boundaries, and more dislocation cores.

Group V Doping in CdSeTe



- XEDS shows small As signal indicating uniform As distribution in CdSeTe.
- No As-clusters are found.



Conclusions

- **Model systems are used to determine grain boundary structures.**
- **Co-passivation for Se and Cl is found to be effective in increasing lifetimes in CdTe devices.**
- **Group V doping was demonstrated in CdSeTe devices.**
- **Grain morphology is affected in Group-V doped CdTe devices.**

Questions?

